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| Notice of References Cited | Application/Control No. 09/845,803 | Applicant(s)/Patent Under Reexamination ZEIRA ET AL. | |
| | Examiner Raj Jain | Art Unit 2664 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-5,461,639 A | 10-1995 | Wheatley et al. | 370/342 |
| | B | US-6,549,785 B1 | 04-2003 | Agin, Pascal | 455/522 |
| | C | US-2002/0016177 | 02-2002 | MIYA et al. | 455/522 |
| | D | US-6,035,210 A | 03-2000 | Endo et al. | 455/522 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
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